

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/585,484	VAN DE WEIJER ET AL.	
		Examiner	Art Unit	Page 1 of 1
		BRIAN R. SLAWSKI	1791	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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	I	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 53005284 A	01-1978	Japan	IWAO, OSAMU	B32B 15/08
	O	JP 11138738 A	05-1999	Japan	YOSHIDA et al.	B41C 1/14
	P	JP 51098779 A	08-1976	Japan	YANASE	B29C 17/10
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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